

Instrument position relative to processing object measuring apparatus - has measuring device for measuring position of instrument including inertia sensor unit

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Equivalents:

Abstract

The position measurement apparatus includes a computer (32) with memory (34) for storage layered images of the processing object (10) with a first coordinate system. A measuring device (16, 18, 20, 22, 24, 26) measures the position of the instrument (12) in a second coordinate system. A further measuring device (20, 22, 24) measures the position of predefined points in the first coordinate system of the processing object in the second coordinate system.

The computer has a coordinate transformation program. The layered image and the instrument in the other coordinate system are displayed on a screen (36). The measuring device for measuring the position of the instrument contains an inertia sensor unit (26).

USE/ADVANTAGE - For use during surgery for example. Enables free handling of instrument and guarantees constant availability of position information.

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